

# Resource Summary Report

Generated by [dkNET](#) on Aug 6, 2026

## FEI: Meridian M System for Semiconductors

RRID:SCR\_019897

Type: Tool

---

### Proper Citation

FEI: Meridian M System for Semiconductors (RRID:SCR\_019897)

---

### Resource Information

**URL:** <https://www.fei.com/products/efa/meridian-m-for-semiconductors/>

**Proper Citation:** FEI: Meridian M System for Semiconductors (RRID:SCR\_019897)

**Description:** Electrical failure analysis system for semiconductors that uses high sensitivity broadband DBX photon emission and Static Laser Stimulation techniques to pinpoint the location of electrical faults.

**Resource Type:** instrument resource

**Keywords:** FEI, EFA System, Instrument Equipment, USEDit,

**Availability:** Commercially available

**Resource Name:** FEI: Meridian M System for Semiconductors

**Resource ID:** SCR\_019897

**Alternate IDs:** Model\_Number\_Meridian\_M

**Record Creation Time:** 20220129T080347+0000

**Record Last Update:** 20260801T190635+0000

---

### Ratings and Alerts

No rating or validation information has been found for FEI: Meridian M System for Semiconductors.

No alerts have been found for FEI: Meridian M System for Semiconductors.

---

### Data and Source Information

**Source:** [SciCrunch Registry](#)

---

## Usage and Citation Metrics

We have not found any literature mentions for this resource.